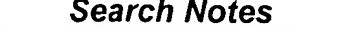


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/697,101	NAYAK ET AL.	
	<b>Examiner</b> Tianjie Chen	<b>Art Unit</b> 2656	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner